Requested Patent:

EP0244951A2

Title:

METHOD AND APPARATUS FOR HANDLING AND PROCESSING WAFER LIKE MATERIALS. ;

Abstracted Patent:

√ EP0244951;

Publication Date:

1987-11-11;

Inventor(s):

HURWITT STEVEN D; EROR MIROSLAV; BIEHL RICHARD E;

Applicant(s):

MATERIALS RESEARCH CORP (US);

Application Number:

EP19870302958 19870403;

Priority Number(s):

US19860848687 19860404;

IPC Classification:

H01L21/00;

Equivalents:

CA1287594, DE3788973D, DE3788973T, JP2637730B2, JP62295421

ABSTRACT:

The apparatus comprises a plenum or main chamber which is divided into two chamber halves. A rotatable index plate is disposed in the chamber. An article to be processed is inserted into a load-lock station formed in the main chamber. After the article is inserted into the load-lock, it is engaged by an article holding device mounted in a position of the rotatable index plate. The index plate is then rotated to a second station, at which a process can be performed upon the substrate, for example, an etching or sputtering process. The process is performed in a processing chamber which is fully isolated from the main chamber and other processing chambers. After rotation by one position, a processed substrate is removed from the load-lock and a new substrate inserted into the load-lock for processing. After a process step is carried out on a substrate, the index plate is again rotated to the next station where another process or removal through the load-lock may be performed.